## Notice of References Cited Application/Control No. 10/080,844 Examiner Han Lieh Liu Applicant(s)/Patent Under R examination LIN ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,093,990	07-2000	Meeks et al.	310/91
*	В	US-5,311,090	05-1994	Ferlatte, Andre A.	310/88
*	С	US-5,209,653	05-1993	Murray et al.	417/410.1
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	К	US-			
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## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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